

AMENDED SPECIFICATION

Conductivity measurements on representative embodiments of the CVD TaN layers give resistivity values below about $5\text{m}\Omega\text{cm}$. The TaSiN with an elemental Si to Ta content ratio between 0.35 and 0.5 yield conductivity values below about $20\text{m}\Omega\text{cm}$. (Resistivity is measured in units of ohm-centimeter (Ωcm), $\text{m}\Omega\text{cm}$ stands for milliohm-centimeter, a thousandths of the ohm-centimeter.)